

**Search Notes**

Application/Control No.

10/749,919

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

YAN ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
363	17		
	56.02		
	56.03		
	56.04		
	56.05		
	56.12		
	98		
	132		
323	252		
	333		
	363		
363	58	5/05	JA

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
363	56.02		
	132		
	98	5/05	JA
323/363		5/05	JA